

FCC TEST REPORT

For

Shenzhen MeiDong Acoustics Co., LTD
Bluetooth headphone

Model No.: E8, E8A, E8B, E8C, E8D, E8E

Prepared For : Shenzhen MeiDong Acoustics Co., LTD

Address Cell B, 3th Floor, Tower B, Hongzhuyongqi Technology Park, Lezhujiao,

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Report Number : SZAWW180411005-01

Date of Test : Apr. 11~18, 2018

Date of Report : Apr. 18, 2018



Contents

1.1. Client Information 1.2 Description of Device (EUT) 1.3. Auxiliary Equipment Used During Test. 1.4. Description of Test Modes 1.5. List of channels. 1.6. Description Of Test Setup. 1.7. Test Equipment Used During Test. 1.8. Measurement Uncertainty. 1.9. Description of Test Facility 1.9. Description of Test Facility 1.9. Description of Test Facility 1.1. Summary of Test Results. 1.3. Conducted Emission Test. 1.3. Test Standard and Limit. 1.4. Test Standard and Limit. 1.5. Test Standard and Limit. 1.6. Test Standard and Limit. 1.7. Test Standard and Limit. 1.8. Test Procedure 1.9. Test Standard and Limit. 1.1. Test Standard and Limit. 1.2. Test Standard and Limit. 1.3. Test Procedure 1.4. Test Data 1.5. Test Standard and Limit. 1.6. Test Standard and Limit. 1.7. Test Standard and Limit. 1.8. Test Standard and Limit. 1.9. Test Standa	1. General Information				VII.	
1.3. Auxiliary Equipment Used During Test 1.4. Description of Test Modes. 1.5. List of channels. 1.6. Description Of Test Setup. 1.7. Test Equipment List. 1.8. Measurement Uncertainty 1 1.9. Description of Test Facility 1 2. Summary of Test Results. 1 3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test 3 6. 1. Test Standard. 3	1.1. Client Information	hoter	Anbe	hotek	Mopore	Arra Colo
1.4. Description of Test Modes. 1.5. List of channels. 1.6. Description Of Test Setup. 1.7. Test Equipment List. 1.8. Measurement Uncertainty. 1 1.9. Description of Test Facility 1 2. Summary of Test Results. 1 3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test. 3 6.1. Test Standard. 3	1.2. Description of Device (EUT)	, botek	Aupore	An	Mpotek	Anbo
1.4. Description of Test Modes. 1.5. List of channels. 1.6. Description Of Test Setup. 1.7. Test Equipment List. 1.8. Measurement Uncertainty. 1 1.9. Description of Test Facility 1 2. Summary of Test Results. 1 3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test. 3 6.1. Test Standard. 3	1.3 Auxiliary Equipment Used Duri	ing Test				
1.6. Description Of Test Setup	1.4. Description of Test Modes	Anbu		rek Vupor	A.n.	ok
1.6. Description Of Test Setup	1.5. List of channels	Anbo	- Alle		otek Anbo	
1.9. Description of Test Facility. 1 2. Summary of Test Results. 1 3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test. 3 6.1. Test Standard. 3	1.6. Description Of Test Setup	1/34	poter Ar	/bc k.	motek ox	pore An
1.9. Description of Test Facility. 1 2. Summary of Test Results. 1 3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test. 3 6.1. Test Standard. 3	1.7. Test Equipment List		- totek	Anbore	VII.	Anhotek An
1.9. Description of Test Facility. 1 2. Summary of Test Results. 1 3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test. 3 6.1. Test Standard. 3	1.8. Measurement Uncertainty	upore	VII.	Repoter	Anbe	1ek
3. Conducted Emission Test. 1 3.1. Test Standard and Limit. 1 3.2. Test Setup. 1 3.3. Test Procedure. 1 3.4. Test Data. 1 4. Radiation Spurious Emission and Band Edge. 1 4.1. Test Standard and Limit. 1 4.2. Test Setup. 1 4.3. Test Procedure. 1 4.4. Test Data. 2 5. Maximum Peak Output Power Test. 2 5.1. Test Standard and Limit. 2 5.2. Test Setup. 2 5.3. Test Procedure. 2 5.4. Test Data. 2 6. 20DB Occupy Bandwidth Test. 3 6.1. Test Standard. 3	1.9. Description of Test Facility	Roboter	Anbe		Anbote	An
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TEST REPORT

Applicant : Shenzhen MeiDong Acoustics Co., LTD

Manufacturer : Shenzhen MeiDong Acoustics Co., LTD

Product Name : Bluetooth headphone

Model No. : E8, E8A, E8B, E8C, E8D, E8E

Trade Mark : COWIN, MEIDONG. Mighty Rock

Rating(s) : Input: DC 5V, 0.2A (with DC 3.7V, 545 mAh Battery inside)

Test Standard(s) : FCC Part15 Subpart C 2017, Section 15.247

Test Method(s) : **ANSI C63.10: 2013**

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the FCC Part 15 Subpart C requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

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Reviewer:		(Pro	oject Manager / Tangcy. T)	
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			Jon Chen	
Approved & Authorized	Signer:		Sk 200	" "Ter
	And hotek		(Manager / Tom Chen)	otek Anbor



1. General Information

1.1. Client Information

Applicant	:	Shenzhen MeiDong Acoustics Co., LTD
Address	:	Cell B, 3th Floor, Tower B, Hongzhuyongqi Technology Park, Lezhujiao, Xixiang, Baoan, Shenzhen, Guangdong, China
Manufacturer	:	Shenzhen MeiDong Acoustics Co., LTD
Address	:	Cell B, 3th Floor, Tower B, Hongzhuyongqi Technology Park, Lezhujiao, Xixiang, Baoan, Shenzhen, Guangdong, China

1.2. Description of Device (EUT)

Product Name	:	Bluetooth headphone	otek Anbotek Anbotek Anti-
Model No.	:	E8, E8A, E8B, E8C, E8D, E8E (Note: The Samples are the same for test only.)	except model no. and exterior, So we prepare "E8"
Trade Mark	:	COWIN, MEIDONG, Mighty Ro	ock Andrew
Test Power Supply	:	AC 120V, 60Hz for adapter/AC 2 DC 3.7V, Battery inside	240V, 60Hz for adapter
		Operation Frequency:	2402MHz~2480MHz
		Transfer Rate:	1/2/3 Mbits/s
Product		Number of Channel:	79 Channels
Description	:	Modulation Type:	GFSK, π/4-DQPSK, 8-DPSK
		Antenna Type:	Ceramic Antenna
		Antenna Gain(Peak):	3.78 dBi

Remark: 1) For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.

1.3. Auxiliary Equipment Used During Test

	Adapter	:	Manufacturer: ZTE	otek	Anbote	Ann	abotek
			M/N: STC-A2050I1000USBA-C				A. notek
eV			S/N: 201202102100876				Ann
			Input: 100-240V~50/60Hz 0.3A		Ann		SK VUPO
00			Output: DC 5V, 1000mA				otek A



1.4. Description of Test Modes

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

Prete	est Mode			Ι	Descriptio	n		
nbotek M	Iode 1	otek	Anbotek	Aupo	CH00	Anbotek	Anbore	Ann
Anbotek M	Iode 2	abotek	Anboten	Aup.	CH39	Anbotek	Anboro	No.
Anbotek M	Iode 3	. nbotek	Anbote	-K	CH78	Anbotel	Anbot	*eK
Anbote N.	Iode 4	Anbo	rek AuK	Leeping T	X+ Char	ging Mode	otek Ani	o.

	For Conducted Emission
Final Test Mode	Description
Mode 4	Keeping TX+ Charging Mode

For Radiated Emission						
Final Test Mode	Description					
Mode 1	CH00 Ann tek obotek A					
Mode 2	CH39					
Mode 3	CH78					
Mode 4	Keeping TX+ Charging Mode					

Note:

- (1) The measurements are performed at the highest, middle, lowest available channels.
 - (2) The data rate was set in 3Mbps for radiated emission due to the highest RF output power.



1.5. List of channels

Channel	Freq. (MHz)	Channel	Freq. (MHz)	Channel	Freq. (MHz)	Channel	Freq. (MHz)	Channel	Freq. (MHz)
00	2402	Anb 17	2419	34	2436	51	2453	68	2470
01	2403	18	2420	35	2437	52	2454	69	2471
02	2404	19	2421	36	2438	53 oten	2455	70	2472
03	2405	20	2422	37	2439	54	2456	71	2473
04	2406	21	2423	38	2440	55	2457	72	2474
05	2407	22	2424	39	2441	56	2458	73	2475
05	2408	23	2425	40	2442	57	2459	74	2476
Let 07 AT	2409	24	2426	41 Anb	2443	58	2460	75	2477
08	2410	25	2427	42 N	2444	59	2461	76	2478
09	2411	26	2428	43	2445	60	2462	ote*77	2479
10	2412	27 📉	2429	44	2446	61 mbo	2463	78	2480
p.I.Pole	2413	28	2430	45	2447	62	2464		
12	2414	29	2431	46	2448	63	2465		
13	2415	30	2432	47,,,,,,,	2449	64	2466		
14	2416	31	2433	48	2450	65	2467	5,00	
15	2417	32	2434	49	2451	66	2468		
16	2418	33	2435	50	2452	67	2469		

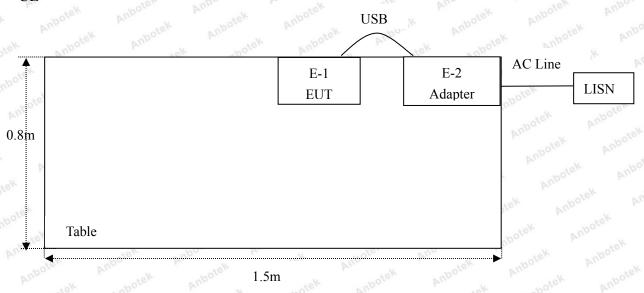
Note:

- 1. The engineering test program was provided and the EUT was programmed to be in continuously transmitting mode.
- 2. EUT built-in battery-powered, fully-charged battery use of the test battery.

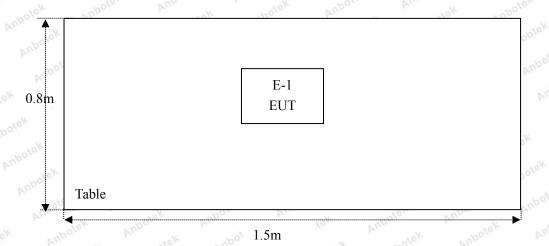


1.6. Description Of Test Setup

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1.7. Test Equipment List

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval	
tek 1. ibotek	L.I.S.N. Artificial Mains Network	Rohde & Schwarz	ENV216	100055	Nov. 17, 2017		
2,00	EMI Test Receiver	Rohde & Schwarz	ESCI	100627	Nov. 17, 2017	1 Year	
3. 🗥	RF Switching Unit	Compliance Direction	RSU-M2	38303	Nov. 17, 2017	1 Year	
4.	Spectrum Analysis	Agilent	E4407B	US39390582	Nov. 17, 2017	1 Year	
5.	Spectrum Analysis	Agilent	N9038A	MY53227295	Nov. 17, 2017	1 Year	
6.	Preamplifier	SKET Electronic	BK1G18G30 D	KD17503	Nov. 17, 2017	1 Year	
7.	EMI Test Receiver	Rohde & Schwarz	ESPI	101604	Nov. 17, 2017	1 Year	
8.	Double Ridged Horn Antenna	Instruments corporation	GTH-0118	351600	Nov. 20, 2017	1 Year	
9.	Bilog Broadband Antenna	Schwarzbeck	VULB9163	VULB 9163-289	Nov. 20, 2017	1 Year	
10.	Loop Antenna	Schwarzbeck	HFH2-Z2	100047	Nov. 17, 2017	1 Year	
11.,,,	Horn Antenna	Schewarzbeck	BBHA9170	9170-375	Nov. 17, 2017	1 Year	
12.	Pre-amplifier	SONOMA	310N	186860	Nov. 17, 2017	1 Year	
13.	EMI Test Software EZ-EMC	SHURPLE	N/A	N/A	N/A	N/A	
14.	RF Test Control System	YIHENG	YH3000	2017430	Nov. 18, 2017	1 Year	
15.	Power Sensor	DAER	RPR3006W	15I00041SN045	Nov. 17, 2017	1 Year	
16.	Power Sensor	DAER	RPR3006W	15I00041SN046	Nov. 17, 2017	1 Year	
17.	MXA Spectrum Analysis	Agilent	N9020A	MY51170037	Nov. 18, 2017	1 Year	
18.	MXG RF Vector Signal Generator	Agilent	N5182A	MY48180656	Nov. 18, 2017	1 Year	
19.	Signal Generator	Agilent	E4421B	MY41000743	Nov. 18, 2017	1 Year	
20.	DC Power Supply	LW	TPR-6410D	349315	Nov. 01, 2017	1 Year	
21.	Constant Temperature Humidity Chamber	Sertep	ZJ-HWHS80 B	ZJ-17042804	Nov. 01, 2017	1 Year	



1.8. Measurement Uncertainty

Radiation Uncertainty	:	Ur = 4.1 dB (Horizontal)
		Ur = 4.3 dB (Vertical)
0		Anbotek Anbotek Anbotek Anbotek Anbotek
Conduction Uncertainty	:	Uc = 3.4dB

1.9. Description of Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC-Registration No.: 184111

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registed and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No. 184111, July 31, 2017.

ISED-Registration No.: 8058A-1

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (ISED) Innovation, Science and Economic Development Canada. The acceptance letter from the ISED is maintained in our files. Registration 8058A-1, June 13, 2016.

Test Location

All Emissions tests were performed at

Shenzhen Anbotek Compliance Laboratory Limited.

at 1/F, Building D, Sogood Science and Technology Park, Sanwei community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China.518102



2. Summary of Test Results

Standard Section	Test Item	Result
15.203/15.247(c)	Antenna Requirement	PASS
15.207	Conducted Emission	PASS
15.205/15.209	Spurious Emission	PASS
15.247(b)(1)	Conducted Peak Output Power	PASS
15.247(a)(1)	20dB Occupied Bandwidth	PASS
15.247(a)(1)	Carrier Frequencies Separation	PASS
15.247(a)(1)	Hopping Channel Number	PASS
15.247(a)(1)	Dwell Time	PASS
15.247(d)	Band Edge	PASS



3. Conducted Emission Test

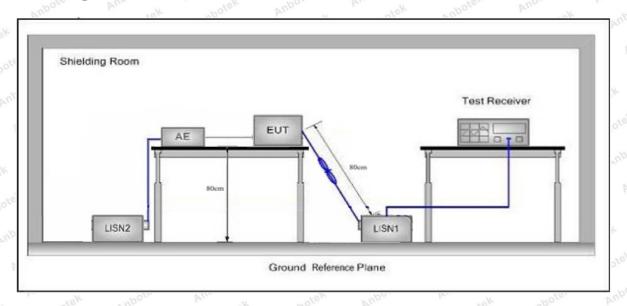
3.1. Test Standard and Limit

C	Test Standard	FCC Part15 Section 15.2	07 Anbore Ans botek	Anbotek Anbo stek
		Ema grand avv	Maximum RF I	Line Voltage (dBuV)
×		Frequency	Quasi-peak Level	Average Level
	Test Limit	150kHz~500kHz	66 ~ 56 *	56 ~ 46 *
6		500kHz~5MHz	56 56 AM	46
0		5MHz~30MHz	Ambotek 60 Ambo	50 botes And

Remark: (1) *Decreasing linearly with logarithm of the frequency.

(2) The lower limit shall apply at the transition frequency.

3.2. Test Setup



3.3. Test Procedure

The EUT system is connected to the power mains through a line impedance stabilization network (L.I.S.N.). This provides a 50ohm coupling impedance for the EUT system. Please refer the block diagram of the test setup and photographs. Both sides of AC line are checked to find out the maximum conducted emission. In order to find the maximum emission levels, the relative positions of equipment and all of the interface cables shall be changed according to FCC ANSI C63.10-2013 on Conducted Emission Measurement.

The bandwidth of test receiver (ESCI) set at 9kHz.

The frequency range from 150kHz to 30MHz is checked.

3.4. Test Data

Please to see the following pages



9

10

11 12 1.6420

2.0660

3.0059

3.2940

12.70

0.00

10.96

-0.16

20.13

20.14

20.16

20.17

32.83

20.14

31.12

20.01

56.00

46.00

56.00

46.00

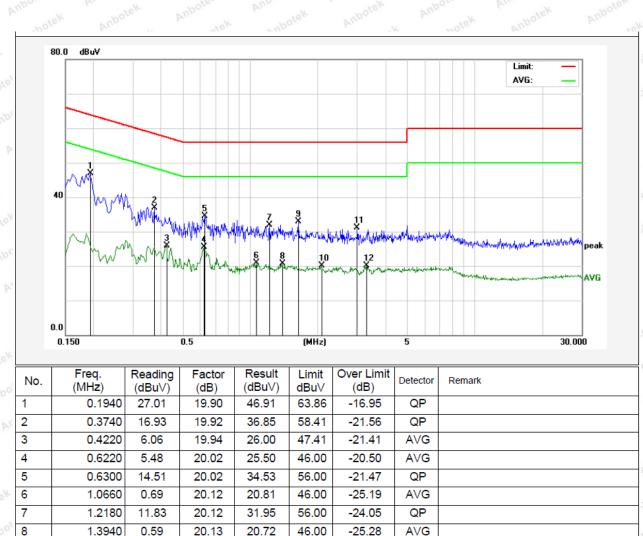
Conducted Emission Test Data

Test Site: 1# Shielded Room

Operating Condition: Keeping TX+ Charging Mode
Test Specification: AC 120V, 60Hz for adapter

Comment: Live Line

Tem.:22.5°C Hum.:59%



QP

AVG

QP

AVG

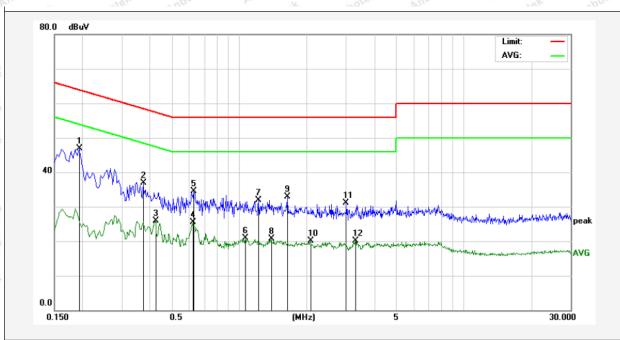
-23.17

-25.86

-24.88

-25.99





No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit dBu∀	Over Limit (dB)	Detector	Remark
1	0.1940	27.01	19.90	46.91	63.86	-16.95	QP	
2	0.3740	16.93	19.92	36.85	58.41	-21.56	QP	
3	0.4220	6.06	19.94	26.00	47.41	-21.41	AVG	
4	0.6220	5.48	20.02	25.50	46.00	-20.50	AVG	
5	0.6300	14.51	20.02	34.53	56.00	-21.47	QP	
6	1.0660	0.69	20.12	20.81	46.00	-25.19	AVG	
7	1.2180	11.83	20.12	31.95	56.00	-24.05	QP	
8	1.3940	0.59	20.13	20.72	46.00	-25.28	AVG	
9	1.6420	12.70	20.13	32.83	56.00	-23.17	QP	
10	2.0660	0.00	20.14	20.14	46.00	-25.86	AVG	
11	3.0059	10.96	20.16	31.12	56.00	-24.88	QP	
12	3.2940	-0.16	20.17	20.01	46.00	-25.99	AVG	



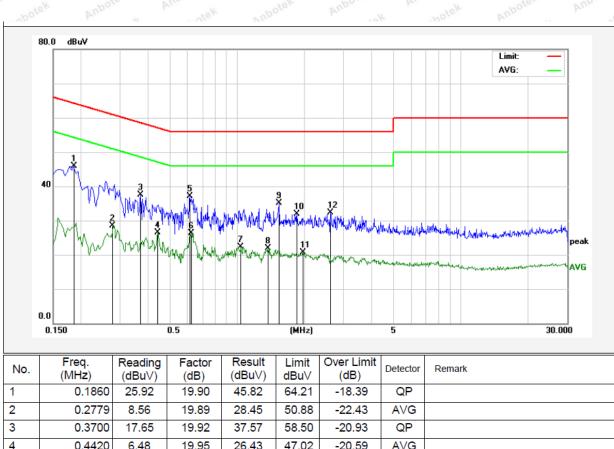
Conducted Emission Test Data

Test Site: 1# Shielded Room

Operating Condition: Keeping TX+ Charging Mode
Test Specification: AC 120V, 60Hz for adapter

Comment: Neutral Line

Tem.:22.5°C Hum.:59%



No.	(MHz)	Reading (dBu∀)	(dB)	(dBuV)	Limit dBu∀	(dB)	Detector	Remark
1	0.1860	25.92	19.90	45.82	64.21	-18.39	QP	
2	0.2779	8.56	19.89	28.45	50.88	-22.43	AVG	
3	0.3700	17.65	19.92	37.57	58.50	-20.93	QP	
4	0.4420	6.48	19.95	26.43	47.02	-20.59	AVG	
5	0.6140	17.17	20.01	37.18	56.00	-18.82	QP	
6	0.6220	6.21	20.02	26.23	46.00	-19.77	AVG	
7	1.0420	2.26	20.12	22.38	46.00	-23.62	AVG	
8	1.3740	1.83	20.13	21.96	46.00	-24.04	AVG	
9	1.5420	14.96	20.13	35.09	56.00	-20.91	QP	
10	1.8500	11.70	20.14	31.84	56.00	-24.16	QP	
11	1.9780	0.47	20.14	20.61	46.00	-25.39	AVG	
12	2.6099	12.07	20.15	32.22	56.00	-23.78	QP	



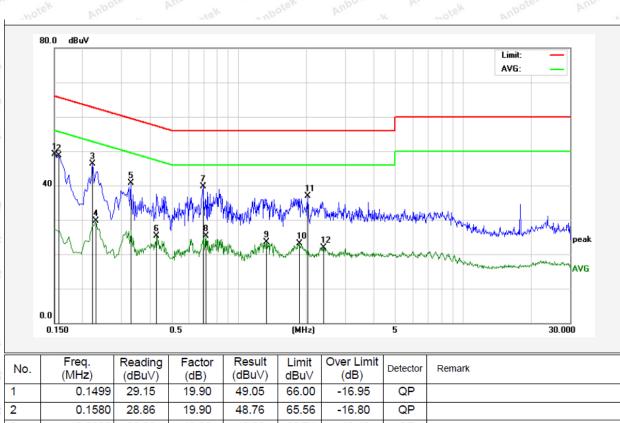
Conducted Emission Test Data

Test Site: 1# Shielded Room

Operating Condition: Keeping TX+ Charging Mode
Test Specification: AC 240V, 60Hz for adapter

Comment: Live Line

Tem.:22.5°C Hum.:59%



5	No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit dBu∀	Over Limit (dB)	Detector	Remark
ſ	1	0.1499	29.15	19.90	49.05	66.00	-16.95	QP	
S	2	0.1580	28.86	19.90	48.76	65.56	-16.80	QP	
Γ	3	0.2220	26.36	19.90	46.26	62.74	-16.48	QP	
Γ	4	0.2300	9.84	19.89	29.73	52.45	-22.72	AVG	
ľ	5	0.3300	20.72	19.90	40.62	59.45	-18.83	QP	
8	6	0.4300	5.39	19.95	25.34	47.25	-21.91	AVG	
	7	0.6900	19.65	20.04	39.69	56.00	-16.31	QP	
Ö	8	0.7140	5.36	20.04	25.40	46.00	-20.60	AVG	
9	9	1.3300	3.29	20.13	23.42	46.00	-22.58	AVG	
9	10	1.8620	2.94	20.14	23.08	46.00	-22.92	AVG	
	11	2.0300	16.69	20.14	36.83	56.00	-19.17	QP	
Γ	12	2.3860	1.84	20.15	21.99	46.00	-24.01	AVG	



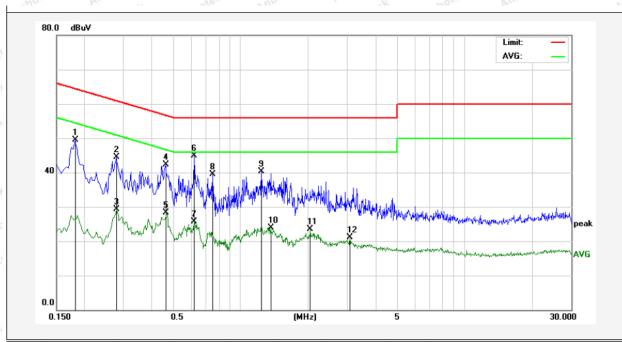
Conducted Emission Test Data

Test Site: 1# Shielded Room

Operating Condition: Keeping TX+ Charging Mode
Test Specification: AC 240V, 60Hz for adapter

Comment: Neutral Line

Tem.:22.5℃ Hum.:59%



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit dBu∀	Over Limit (dB)	Detector	Remark
1	0.1819	29.52	19.90	49.42	64.39	-14.97	QP	
2	0.2779	24.60	19.89	44.49	60.88	-16.39	QP	
3	0.2779	9.35	19.89	29.24	50.88	-21.64	AVG	
4	0.4620	22.30	19.96	42.26	56.66	-14.40	QP	
5	0.4660	8.43	19.96	28.39	46.58	-18.19	AVG	
6	0.6180	24.90	20.02	44.92	56.00	-11.08	QP	
7	0.6180	5.65	20.02	25.67	46.00	-20.33	AVG	
8	0.7500	19.44	20.05	39.49	56.00	-16.51	QP	
9	1.2420	20.10	20.12	40.22	56.00	-15.78	QP	
10	1.3619	3.87	20.13	24.00	46.00	-22.00	AVG	
11	2.0540	3.44	20.14	23.58	46.00	-22.42	AVG	
12	3.0740	0.96	20.16	21.12	46.00	-24.88	AVG	



4. Radiation Spurious Emission and Band Edge

4.1. Test Standard and Limit

Test Standard	FCC Part15 C Section 15.2	209 and 15.205	Am	Anbotek	Aupo, stek
	Frequency (MHz)	Field strength (microvolt/meter)	Limit (dBuV/m)	Remark	Measurement distance (m)
	0.009MHz~0.490MHz	2400/F(kHz)	obotek - Anbo	o Pun	300
	0.490MHz-1.705MHz	24000/F(kHz)	Anbotek Ar	Pore Vin	note 30
	1.705MHz-30MHz	30	Anbatek	Anbore A	30
Test Limit	30MHz~88MHz	100	40.0	Quasi-peak	3.ek
	88MHz~216MHz	150	43.5	Quasi-peak	3 _{botek}
	216MHz~960MHz	200	46.0	Quasi-peak	iek 3 nbotek
	960MHz~1000MHz	500	54.0	Quasi-peak	stek 3 anbo
	Above 1000MHz	500	54.0	Average	del3
	Above 1000MHz	botek - Anbot	74.0	Peak	Anno 3

Remark:

- (1)The lower limit shall apply at the transition frequency.
- (2) 15.35(b), Unless otherwise specified, the limit on peak radio frequency emissions is 20dB above the maximum permitted average emission limit applicable to the equipment under test. This peak limit applies to the total peak emission level radiated by the device.

4.2. Test Setup

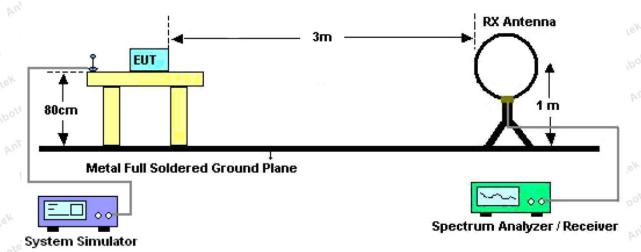


Figure 1. Below 30MHz

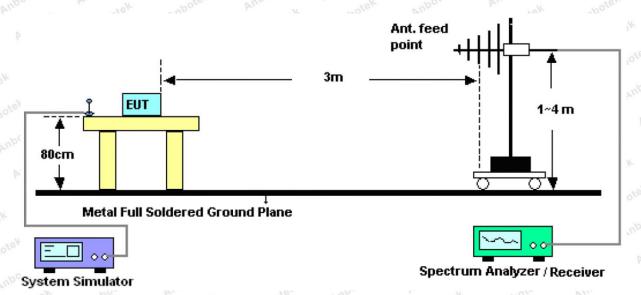


Figure 2. 30MHz to 1GHz

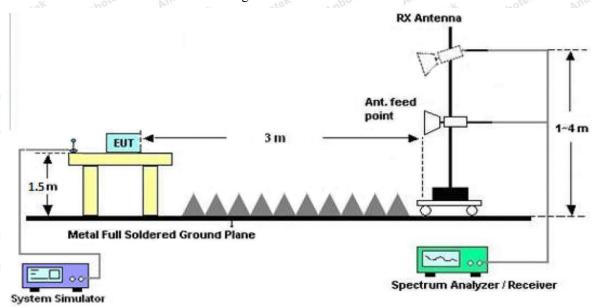


Figure 3. Above 1 GHz

4.3. Test Procedure

For below 1GHz: The EUT is placed on a turntable, which is 0.8m above the ground plane.

For above 1GHz: The EUT is placed on a turntable, which is 1.5m above the ground plane.

The turn table can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 3 meters away from the receiving antenna which is mounted on a antenna tower. The antenna can be moved up and down from 1 to 4 meters to find out the maximum emission level. Rotated the EUT through three orthogonal axes to determine the maximum emissions, both horizontal and vertical polarization of the antenna are set on test. The EUT is tested in 9*6*6 Chamber. The device is evaluated in xyz orientation.

For the radiated emission test above 1GHz:

Place the measurement antenna away from each area of the EUT determined to be a source of emissions at the specified measurement distance, while keeping the measurement antenna aimed at the source of emissions at each frequency of significant emissions, with polarization oriented for maximum response. The measurement antenna may have to be higher or lower than the EUT, depending on the radiation pattern of the emission and staying



aimed at the emission source for receiving the maximum signal. The final measurement antenna elevation shall be that which maximizes the emissions. The measurement antenna elevation for maximum emissions shall be restricted to a range of heights of from 1 m to 4 m above the ground or reference ground plane.

For 9kHz to 150kHz, Set the spectrum analyzer as:

RBW = 200Hz, VBW = 1kHz, Detector= Quasi-Peak, Trace mode= Max hold, Sweep- auto couple.

For 150kHz to 30MHz, Set the spectrum analyzer as:

RBW = 9KHz, VBW = 30kHz, Detector= Quasi-Peak, Trace mode= Max hold, Sweep- auto couple.

For 30MHz to 1000MHz, Set the spectrum analyzer as:

RBW = 100kHz, VBW = 300kHz, Detector = Quasi-Peak, Trace mode = Max hold, Sweep- auto couple.

For above 1GHz, Set the spectrum analyzer as:

RBW =1MHz, VBW =1MHz, Detector= Peak, Trace mode= Max hold, Sweep- auto couple.

RBW =1MHz, VBW =10Hz, Detector= Average, Trace mode= Max hold, Sweep- auto couple.

4.4. Test Data

PASS

During the test, pre-scan the GFSK, $\pi/4$ QPSK, 8DPSK modulation, and found the GFSK modulation which is worse case.

The test results of 9kHz-30MHz was attenuated more than 20dB below the permissible limits, so the results don't record in the report.

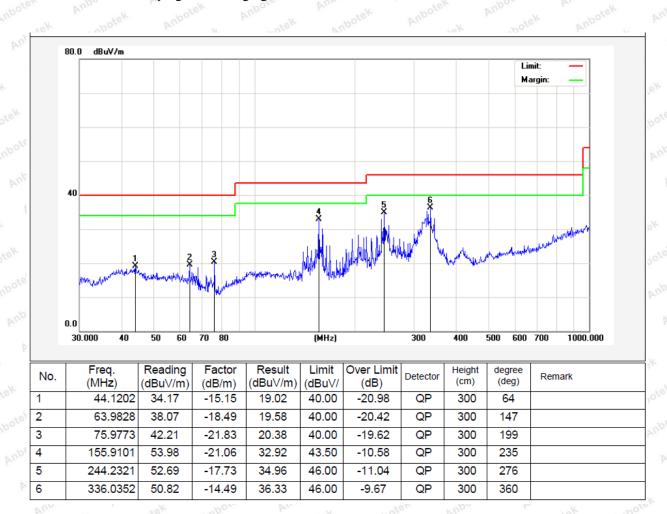


Test Results (30~1000MHz)

Job No.: SZAWW180411005-01 Temp.(°C)/Hum.(%RH): 23.2°C/54%RH

Standard: FCC PART 15C Power Source: DC 3.7V, Battery inside

Test Mode: Keeping TX+ Charging Mode Polarization: Horizontal



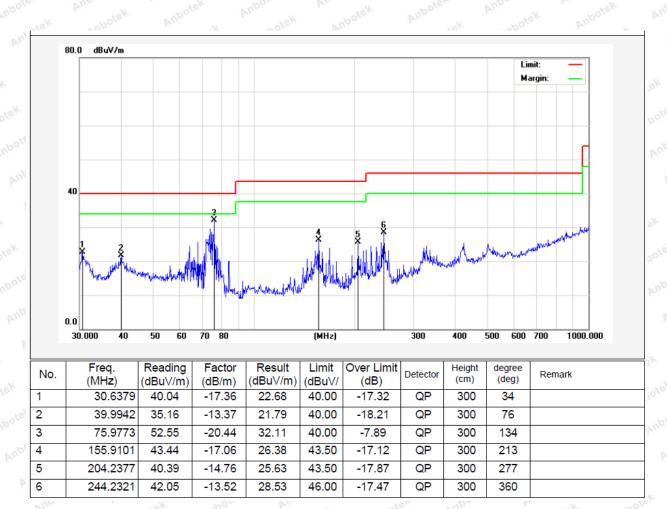


Test Results (30~1000MHz)

Job No.: SZAWW180411005-01 Temp.(°C)/Hum.(%RH): 23.2°C/54%RH

Standard: FCC PART 15C Power Source: DC 3.7V, Battery inside

Test Mode: Keeping TX+ Charging Mode Polarization: Vertical





Test Results (1GHz-25GHz)

Test Mode: 0	CH00			Test	channel: Lowe	est		
				Peak Value				
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.
4804.00	38.46	34.04	6.58	34.09	44.99	74.00	-29.01	bot V
7206.00	32.60	37.11	7.73	34.50	42.94	74.00	-31.06	Na Vel
9608.00	32.15	39.31	9.23	34.79	45.90	74.00	-28.10	V
12010.00	*	tek L	ibotek p	upor	An potek	74.00	Anbo	V
14412.00	* Aup	atek .	nbotek	Aupoten	Aur	74.00	Anbor	V
4804.00	42.98	34.04	6.58	34.09	49.51	74.00	-24.49	Н
7206.00	34.45	37.11	7.73	34.50	44.79	74.00	-29.21	H
9608.00	31.68	39.31	9.23	34.79	45.43	74.00	-28.57	Anboro H
12010.00	*nbote*	Aupo	rek Vi	botek	Anboten	74.00	Anbotek	PĤ
14412.00	ek * Anbo	Kek Ar	loor b	abotek	Anborek	74.00	Anbotek	HA
3			A	verage Valu	e			
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.
4804.00	27.06	34.04	6.58	34.09	33.59	54.00	-20.41	V
7206.00	21.15	37.11	7.73	34.50	31.49	54.00	-22.51	V
9608.00	20.16	39.31	9.23	34.79	33.91	54.00	-20.09	V
12010.00	poter * Ar	loor.	botek	Anbotes	Anbo	54.00	Anbos	V
14412.00	*	Anbor	An botek	Anbote	Ambo	54.00	cek An	V
4804.00	31.41	34.04	6.58	34.09	37.94	54.00	-16.06	Aupoter.
7206.00	23.40	37.11	7.73	34.50	33.74	54.00	-20.26	ΜĤ
9608.00	19.98	39.31	9.23	34.79	33.73	54.00	-20.27	Hari
12010.00	tek *	potek	Yupore.	Anotek abotek	Anbotek	54.00	Au	Н
14412.00	*	botek	Anboter	Nun-	k abote	54.00	er by	ote ^k H



Test Results (1GHz-25GHz)

Test Mode: 0	CH39			Test	channel: Midd	le		
				Peak Value				
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.
4882.00	36.57	34.38	6.69	34.09	43.55	74.00	-30.45	boteV
7323.00	31.34	37.22	7.78	34.53	41.81	74.00	-32.19	Vel
9764.00	31.04	39.46	9.35	34.80	45.05	74.00	-28.95	V
12205.00	*	tek v	ibotek p	upoto	An abotek	74.00	Anbo	V
14646.00	* 4	atek	anbotek	Aupoten	Ann	74.00	Aupor	V
4882.00	40.71	34.38	6.69	34.09	47.69	74.00	-26.31	Н
7323.00	33.03	37.22	7.78	34.53	43.50	74.00	-30.50	H
9764.00	30.39	39.46	9.35	34.80	44.40	74.00	-29.60	Anbore
12205.00	*nbote*	Aupo	* 6 K	botek	Anboten	74.00	anbotek	PĤ
14646.00	lek * Anbo	Kek Ar	loor b	spotek	Anborek	74.00	Anbotek	HA
			A	verage Valu	e			
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.
4882.00	25.54	34.38	6.69	34.09	32.52	54.00	-21.48	V
7323.00	20.12	37.22	7.78	34.53	30.59	54.00	-23.41	V
9764.00	19.24	39.46	9.35	34.80	33.25	54.00	-20.75	V
12205.00	potek * Ar	Por	botek	Aupoles	Ambo	54.00	Anbox	V
14646.00	Anbote*	Anbore	An botek	Anbott	Ambo	54.00	Lek An	V
4882.00	29.68	34.38	6.69	34.09	36.66	54.00	-17.34	Auporen
7323.00	22.25	37.22	7.78	34.53	32.72	54.00	-21.28	ÞĤ
9764.00	18.91	39.46	9.35	34.80	32.92	54.00	-21.08	Ho
12205.00	tek *	potek	Yupore.	And wotek	Anbotek	54.00	A. soote	Н
14646.00	*	bosek	Aupoter	Nun-	k abote	54.00	-/r	ote ^K H



Test Results (1GHz-25GHz)

Test Mode: 0	CH78			Test	channel: High	est		
				Peak Value				
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.
4960.00	36.06	34.72	6.79	34.09	43.48	74.00	-30.52	voteV
7440.00	31.01	37.34	7.82	34.57	41.60	74.00	-32.40	Vel
9920.00	30.74	39.62	9.46	34.81	45.01	74.00	-28.99	V
12400.00	*	tek v	ibotek p	upor	An.	74.00	Aupo	V
14880.00	* Anb	ntek.	Anbotek	Anboten	Yun Potek	74.00	Mupor	v V
4960.00	40.10	34.72	6.79	34.09	47.52	74.00	-26.48	Н
7440.00	32.65	37.34	7.82	34.57	43.24	74.00	-30.76	H
9920.00	30.04	39.62	9.46	34.81	44.31	74.00	-29.69	Anbote H
12400.00	*nbotel	Aupo	* GK	botek	Anboten	74.00	Anbotek	PĤ
14880.00	ek * Anbe	Kek Ar	loor b	Sporek	Anboren	74.00	anbotek	HA
-33			A	verage Valu	e			
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.
4960.00	25.16	34.72	6.79	34.09	32.58	54.00	-21.42	V
7440.00	19.87	37.34	7.82	34.57	30.46	54.00	-23.54	V
9920.00	19.02	39.62	9.46	34.81	33.29	54.00	-20.71	V
12400.00	potek * Ar	Por	botek	Anboren	Ambo	54.00	Anbox	V
14880.00	Anbotek	Anbore	An botek	Anboth	Ambo	54.00	rek An	V
4960.00	29.26	34.72	6.79	34.09	36.68	54.00	-17.32	Auporen
7440.00	21.96	37.34	7.82	34.57	32.55	54.00	-21.45	ÞΉ
9920.00	18.65	39.62	9.46	34.81	32.92	54.00	-21.08	Ho
12400.00	stek *	potek	Yupore.	Andrek	Anbotek	54.00	Ai.	Н
14880.00	*	potek	Aupoter	Vun.	k abote	54.00	-/c	o ^{tel} H

Remark

- 1. During the test, pre-scan the GFSK, $\pi/4$ QPSK, 8DPSK modulation, and found the GFSK modulation is worse case, the report only record this mode.
- 2. Level =Receiver Read level + Antenna Factor + Cable Loss Preamplifier Factor
- 3. "*" means the test results were attenuated more than 20dB below the permissible limits, so the results don't record in the report.



Radiated Band Edge:

Test Mode: 0	CH00			Test	Test channel: Lowest						
				Peak Value							
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.			
2390.00	43.75	29.15	3.41	34.01	42.30	74.00	-31.70	Hek			
2400.00	60.66	29.16	3.43	34.01	59.24	74.00	-14.76	H			
2390.00	44.38	29.15	3.41	34.01	42.93	74.00	-31.07	V			
2400.00	62.79	29.16	3.43	34.01	61.37	74.00	-12.63	V			
			A	verage Valu	e						
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.			
2390.00	34.10	29.15	3.41	34.01	32.65	54.00	-21.35	Hoo			
2400.00	45.39	29.16	3.43	34.01	43.97	54.00	-10.03	H			
2390.00	34.11	29.15	3.41	34.01	32.66	54.00	-21.34	V V			
2400.00	47.12	29.16	3.43	34.01	45.70	54.00	-8.30	V			

Test Mode: 0	CH78			Test	Test channel: Highest						
				Peak Value							
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.			
2483.50	45.95	29.28	3.53	34.03	44.73	74.00	-29.27	$^{\prime\prime}$ $^{\prime\prime}$ $^{\prime\prime}$			
2500.00	44.96	29.30	3.56	34.03	43.79	74.00	-30.21	Hot			
2483.50	46.94	29.28	3.53	34.03	45.72	74.00	-28.28	V			
2500.00	46.04	29.30	3.56	34.03	44.87	74.00	-29.13	V			
		10	A	verage Valu	e	153					
Frequency (MHz)	Read Level (dBuV)	Antenna Factor (dB/m)	Cable Loss (dB)	Preamp Factor (dB)	Level (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	Pol.			
2483.50	36.94	29.28	3.53	34.03	35.72	54.00	-18.28	A/Hote			
2500.00	34.82	29.30	3.56	34.03	33.65	54.00	-20.35	Har			
2483.50	38.22	29.28	3.53	34.03	37.00	54.00	-17.00	V			
2500.00	34.81	29.30	3.56	34.03	33.64	54.00	-20.36	tek V			

Remark:

- 1. During the test, pre-scan the GFSK, $\pi/4$ QPSK, 8DPSK modulation, and found the GFSK modulation is worse case, the report only record this mode.
- 2. Level = Receiver Read level + Antenna Factor + Cable Loss Preamplifier Factor

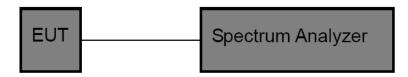


5. Maximum Peak Output Power Test

5.1. Test Standard and Limit

Test Standard	FCC Part15 C Se	ection 15.247	'(b)(3)	An. botek	Anbotek	Anboatek
Test Limit	1W or 125 mW	Anbotek	Aupor	All.	Anbotek	Anbo

5.2. Test Setup



5.3. Test Procedure

- 1. The EUT was directly connected to the spectrum analyzer and antenna output port as show in the block diagram above,
- 2. Spectrum Setting:

RBW > the 20 dB bandwidth of the emission being measured

Span = approximately 5 times the 20 dB bandwidth, centered on a hopping channel

 $VBW \ge RBW$

Sweep = auto

Detector function = peak

Trace = max hold

5.4. Test Data

Test Item	:	Max. peak output power	Test Mode :	CH Low ~ CH High
Test Voltage	:	DC 3.7V, Battery inside	Temperature :	24°C
Test Result		PASS	Humidity .	55%RH

Channel Frequency (MHz)	Peak Power output (dBm)	Limit (dBm)	Results	Modulation
2402	-1.206	30 mboles	PASS	BDR
2441	-1.302	30	PASS	BDR
2480	-0.912	30	PASS	BDR
2402	-1.357	20.96	PASS	EDR
2441	-1.470	20.96	PASS	EDR
2480	-1.157	20.96	PASS	EDR

Remark: The EDR was tested on $(\pi/4DQPSK, 8DPSK)$ modes, only the worst data of (8DPSK) is attached in the following pages.



Test Mode: BDR---Low



Test Mode: BDR---Middle



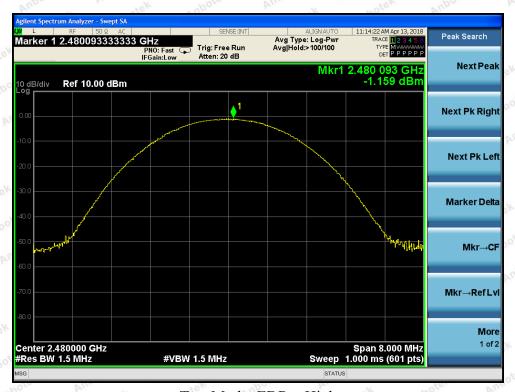
Test Mode: BDR---High



Test Mode: EDR---Low



Test Mode: EDR---Middle



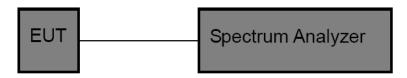
Test Mode: EDR---High



6. 20DB Occupy Bandwidth Test

6.1. Test Standard

6.2. Test Setup



6.3. Test Procedure

Using the following spectrum analyzer settings:

- 1. Span= approximately 2 to 3 times the 20dB bandwidth, centered on a hopping channel.
- 2. Set the RBW = 30 kHz.
- 3. Set the VBW = 100 kHz.
- 4. Sweep time = auto couple.
- 5. Detector function = peak.
- 6. Trace mode = max hold.
- 7. Allow trace to fully stabilize.

6.4. Test Data

Test Item : 20dB BW Test Mode : CH Low ~ CH High

Test Voltage : DC 3.7V, Battery inside Temperature : 24° C Test Result : PASS Humidity : 55° RH

Channel	Frequency(MHz)	20dB Down BW(kHz)	Modulation Mode
Low	2402	930.0	BDR
Middle	2441	935.7	BDR
High	2480	929.7	BDR
Low	2402	1267.0	EDR
Middle	2441	1266.0	EDR
High	2480	1268.0	EDR
on 1 millions	1 (UD ODGY OD	narry and a district of	(ODDOTT) :

Remark: The EDR was tested on $(\pi/4DQPSK, 8DPSK)$ modes, only the worst data of (8DPSK) is attached in the following pages.



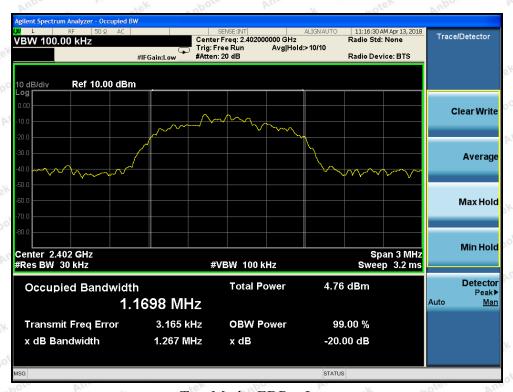
Test Mode: BDR---Low



Test Mode: BDR---Middle



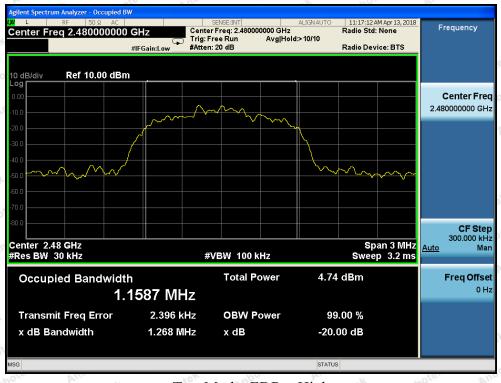
Test Mode: BDR---High



Test Mode: EDR---Low



Test Mode: EDR---Middle



Test Mode: EDR---High

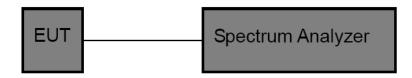


7. Carrier Frequency Separation Test

7.1. Test Standard and Limit

70	Test Standard	FCC Part15 C Section 15.247 (a)(1)	Anbotek	Anbo stek
	Test Limit	>25KHz or >two-thirds of the 20 dB bandwidth	Anboten	Anbo

7.2. Test Setup



7.3. Test Procedure

The EUT must have its hopping function enabled. Using the following spectrum analyzer settings:

- 1. Span= Wide enough to capture the peaks of two adjacent channels
- 2. Set the RBW = 30 kHz.
- 3. Set the VBW = 100 kHz.
- 4. Sweep time = auto couple.
- 5. Detector function = peak.
- 6. Trace mode = max hold.
- 7. Allow trace to fully stabilize.

7.4. Test Data

Test Item	:	Frequency Separation	Test Mode :	CH Low ~ CH High
Test Voltage	:	DC 3.7V, Battery inside	Temperature :	24 °C
Test Result	:	PASS	Humidity :	55%RH

Channal	Frequency	Separation Read	Limit	Modulation
Channel	(MHz)	Value (kHz)	(kHz)	Mode
Low	2402	1000	930.0	BDR
Middle	2441	1000	935.7	BDR
High	2480	1000	929.7	BDR
Low	2402	1000	844.7	EDR
Middle	2441	1000	844.0	EDR
High	2480	1000	845.3	EDR

Remark:

- 1. The limit of mode (EDR) is 2/3 of 20dB BW;
- 2. The EDR was tested on (π /4DQPSK, 8DPSK) modes, only the worst data of (8DPSK) is attached in the following pages.



Test Mode: BDR---Low



Test Mode: BDR---Middle



Test Mode: BDR---High



Test Mode: EDR---Low



Test Mode: EDR---Middle



Test Mode: EDR---High



8. Number of Hopping Channel Test

8.1. Test Standard and Limit

or,	Test Standard	FCC Part15 C	Section 15.2	47 (a)(1)	Ambotek	Anbotek	Anbo	þ.
	Test Limit	>15 channels	Anbotek	Aupor	Air	Anbotek	Anboatek	

8.2. Test Setup



8.3. Test Procedure

The EUT must have its hopping function enabled. Using the following spectrum analyzer setting:

- 1. Span= the frequency band of operation
- 2. Set the RBW = 100kHz.
- 3. Set the VBW = 300kHz.
- 4. Sweep time = auto couple.
- 5. Detector function = peak.
- 6. Trace mode = max hold.
- 7. Allow trace to fully stabilize.

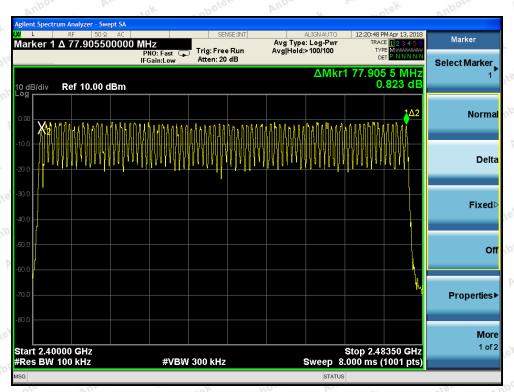
8.4. Test Data

Test Item : Number of Hopping Frequency Test Mode : CH Low ~ CH High

Test Voltage : DC 3.7V, Battery inside Temperature : 24° C Test Result : PASS Humidity : 55° RH

Hopping Channel Frequency		Quantity of Hopping Channel	Quantity of Hopping Channel		
5	Range				
	2402-2480MHz	79 Tel	>15		





BDR Mode



EDR Mode

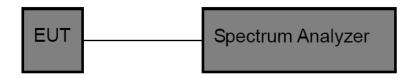


9. Dwell Time Test

9.1. Test Standard and Limit

O,	Test Standard	FCC Part15 C	Section 15.2	47 (a)(1)	hotek	Anbotek	Anbo	7
	Test Limit	0.4 sec	Anbotek	Anbote	Anhotek	Anboten	Anboatek	P

9.2. Test Setup



9.3. Test Procedure

The EUT must have its hopping function enabled. Use the following spectrum analyzer settings:

- 1. Span= zero span, centered on a hopping channel
- 2. Set the RBW = 1 MHz.
- 3. Set the VBW = 1 MHz.
- 4. Sweep time = as necessary to capture the entire dwell time per hopping channel.
- 5. Detector function = peak.
- 6. Trace mode = max hold.
- 7. Allow trace to fully stabilize.

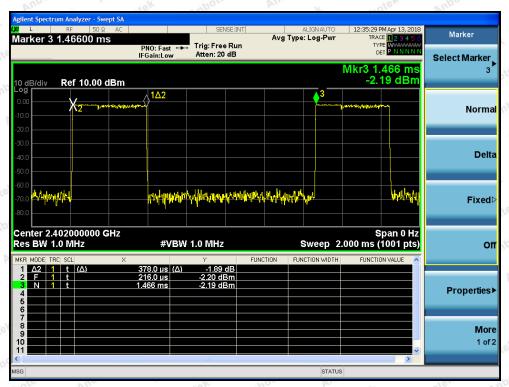
9.4. Test Data

Test Item : Time of Occupancy Test Mode : CH Low ~ CH High

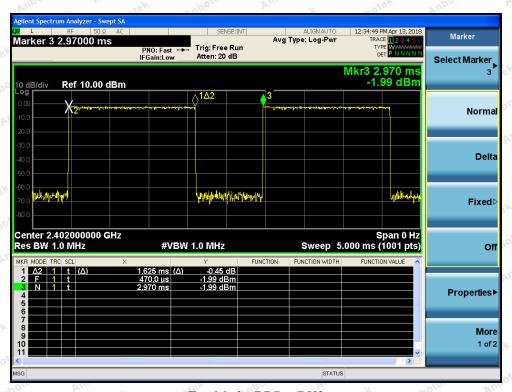
Test Voltage : DC 3.7V, Battery inside Temperature : 24° C Test Result : PASS Humidity : 55° RH

Package Type	Pulse width (ms)	Time slot length(ms)	Dwell time (ms)	Limit (s)	Modulation
DH1	0.378	time slot length *1600/2 /79 * 31.6	120.96	0.4	BDR
DH3	1.625	time slot length *1600/4 /79 * 31.6	260.00	0.4	BDR
DH5	2.880	time slot length *1600/6 /79 * 31.6	307.20	0.4	BDR MO
3DH1	0.378	time slot length *1600/2 /79 * 31.6	120.96	0.4	EDR
3DH3	1.625	time slot length *1600/4 /79 * 31.6	260.00	0.4	EDR
3DH5	2.872	time slot length *1600/6 /79 * 31.6	306.35	0.4	EDR

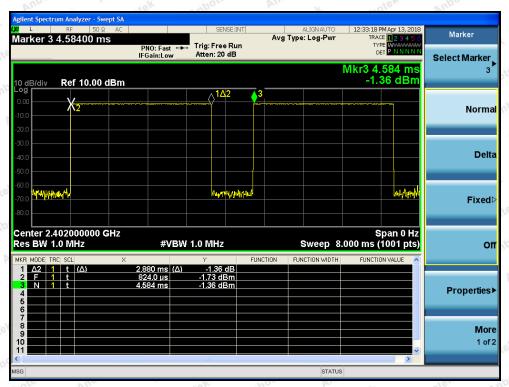
Remark: The EDR was tested on (π /4DQPSK, 8DPSK) modes, only the worst data of (8DPSK) is attached in the following pages.



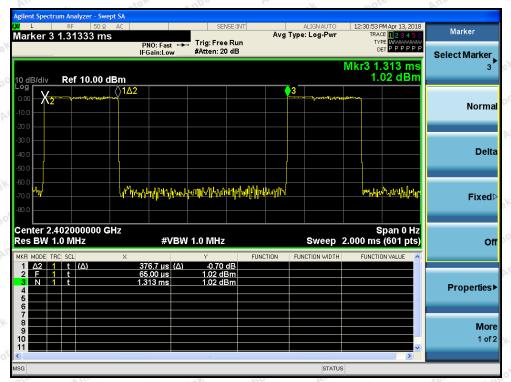
Test Mode: BDR---DH1



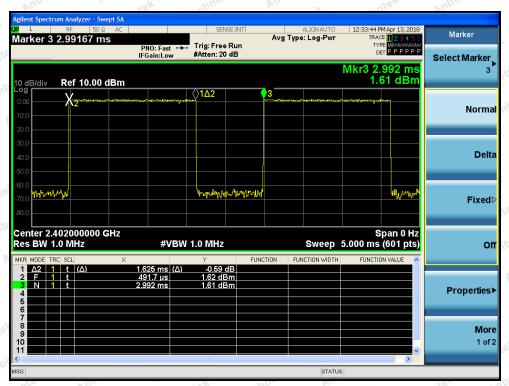
Test Mode: BDR---DH3



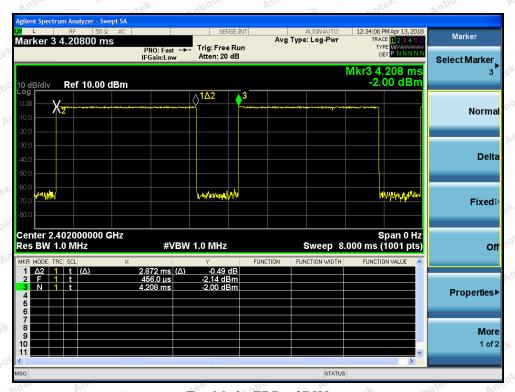
Test Mode: BDR—DH5



Test Mode: EDR---3DH1



Test Mode: EDR---3DH3



Test Mode: EDR—3DH5



10. 100kHz Bandwidth of Frequency Band Edge Requirement

10.1. Test Standard and Limit

Test Standard	FCC Part15 C Section 15.247 (d)
Test Limit	in any 100 kHz bandwidth outside the frequency bands in which the spread spectrum intentional radiator in operating, the radio frequency power that is produced by the intentional radiator shall be at least 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, In addition, radiated emissions which fall in the restricted bands, as defined in §15.205(a), must also comply with the radiated emission limits specified in 15.209(a).

10.2. Test Setup



10.3. Test Procedure

The EUT must have its hopping/Non-hopping function enabled. Using the following spectrum analyzer setting:

- 1. Set the RBW = 100kHz.
- 2. Set the VBW = 300kHz.
- 3. Sweep time = auto couple.
- 4. Detector function = peak.
- 5. Trace mode = max hold.
- 6. Allow trace to fully stabilize.

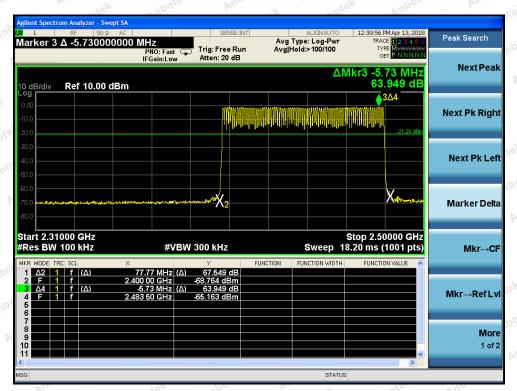
10.4. Test Data

Test Item : Band edge : CH Low ~ CH High
Test Voltage : DC 3.7V, Battery inside : Temperature : 24°C
Test Result : PASS : Humidity : 55%RH

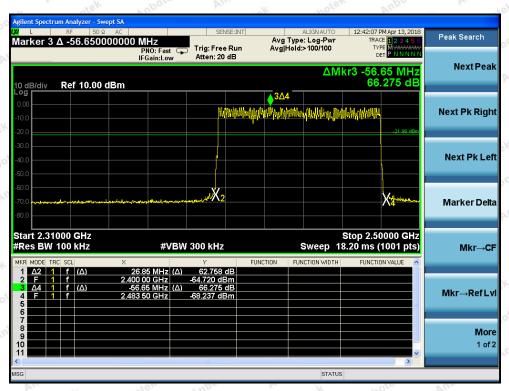
Remark: The EDR was tested on (π /4DQPSK, 8DPSK) modes, only the worst data of (π /4DQPSK) is attached in the following pages.



For Hopping Mode



BDR mode



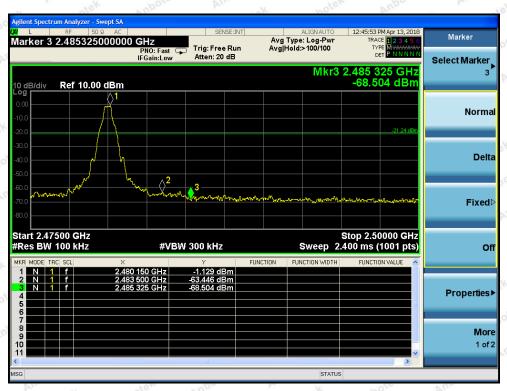
EDR mode



For Non-Hopping Mode



BDR mode -- Lowest



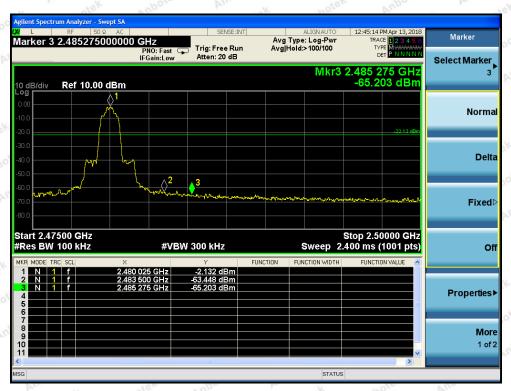
BDR mode -- Highest



For Non-Hopping Mode



EDR mode -- Lowest



EDR mode -- Highest

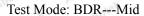


Conducted Emission Method





Test Mode: BDR---Low







Test Mode: BDR---High

Test Mode: EDR---Low





Test Mode: EDR---Mid

Test Mode: EDR---High



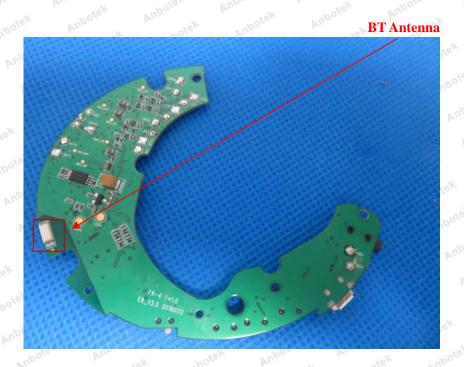
11. Antenna Requirement

11.1. Test Standard and Requirement

Test Standard	FCC Part15 Section 15.203 /247(c)
	1) 15 202 mass manufactors Anbores Anbores Anbores
	1) 15.203 requirement:
	An intentional radiator shall be designed to ensure that no antenna other than that furnished
	by the responsible party shall be used with the device. The use of a permanently
	attached antenna or of an antenna that uses a unique coupling to the intentional radiator, the
	manufacturer may design the unit so that a broken antenna can be replaced by the user, but
Requirement	the use of a standard antenna jack or electrical connector is prohibited.
	2) 15.247(c) (1)(i) requirement:
	Systems operating in the 2400-2483.5 MHz band that is used exclusively for fixed.
	Point-to-point operations may employ transmitting antennas with directional gain greater
	than 6dBi provided the maximum conducted output power of the intentional radiator is
	reduced by 1 dB for every 3 dB that the directional gain of the antenna exceeds 6 dBi.

11.2. Antenna Connected Construction

The bluetooth antenna is ceramic Antenna which permanently attached, and the best case gain of the antenna is 3.78 dBi. It complies with the standard requirement.





APPENDIX I -- TEST SETUP PHOTOGRAPH

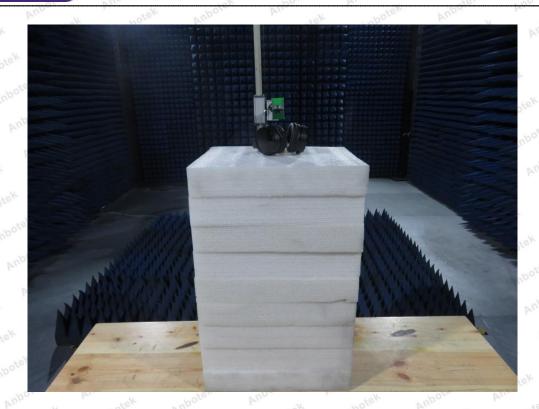
Photo of Conducted Emission Measurement



Photo of Radiation Emission Test









APPENDIX II -- EXTERNAL PHOTOGRAPH

























APPENDIX III -- INTERNAL PHOTOGRAPH



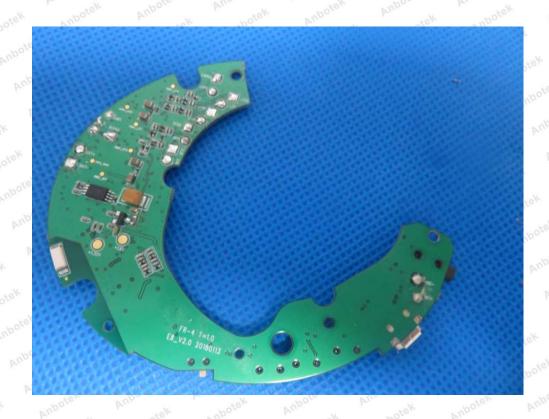














End of Report